Docket No.: 4425-168

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

JAN 26 2004

In re Application of

LU, YEN-TING

U.S. Patent Application No. 09/919,8

Filed: August 2, 2001

Group Art Unit: 1756

Examiner: YOUNG, CHRISTOPHER G.

For: METHOD FOR REDUCING LINE EDGE ROUGHNESS OF PHOTORESIST

Dear Sir:

Transmitted herewith is an Amendment in the above identified application.

No additional fee is required.

Small entity status of this application has been established.

Also attached:

The fee has been calculated as shown below:

| | NO. OF CLAIMS | HIGHEST PREVIOUSLY PAID FOR | EXTRA CLAIMS | RATE | FEE | E |
|--------------------|--|-----------------------------------|-----------------|---------------|-----|------|
| Total Claims | 33 | 33 | 0 | x \$ 18 = | \$ | 0.00 |
| Independent Claims | 3 | 3 | 0 | x \$ 86 = | \$ | 0.00 |
| | If multiple claims newly presented, add \$290.00 Fee for extension of time | | | | | |
| | | | | TOTAL FEE DUE | \$ | 0.00 |

A credit card authorization form in the amount of ______ is attached

The Commissioner is hereby authorized to charge payment of any fees associated with this communication or credit any overpayment, to Deposit Account No. <u>07-1337</u>, including any filing fees under 37 CFR 1.16 for presentation of extra claims and any patent application processing fees under 37 CFR 1.17.

Respectfully submitted,

WE HAUPTMAN GILMAN & BERNER, LLP

Benjamin J. Hauptman Registration No.: 29,310

1700 Diagonal Road, Suite 300 Alexandria, Virginia 22314 (703) 684-1111 (703) 518-5499 Facsimile Date: January 21, 2004 BJH/jk